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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Apstron Serial No	
	4634
Filing Date	August 31, 2000
	Garo J. Derderian et al.
Assignee	Micron Technology, Inc.
	2818
Examiner	T. Lee
Customer No	021567
Attorney's Docket No	Ml22-1330
Title: Capacitor Fabrication Me	ethods Including Forming a Conductive Layer

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Reference -See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

Citation of these references is respectfully requested.

Respectfully submitted,

Dated: 16 01 + 2006

By:

Reg. No. 44,854

Form PTO-1449			U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1330			SERIAL NO. 09/653,149			
		LIST OF ART CITED	BY APPLICAN	NT.	APPLICANT: Garo J. Derderian et al.							
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*Examiner's Initials		Document Number	Date	Name		Class	Subclass		Filing Date If Appropriate			
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OTHER RE	FEREN	ICES (including Author,	Title, Date, Pe	ertinent Pages, Etc.)								
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EXAMINER DATE CONSIDERED												
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.												